When will low-contrast features be visible in a STEM X-ray spectrum image?

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Under what circumstances will a low-contrast feature, such as a nanoparticle embedded in a foil prepared for transmission electron microscopy (TEM), be visible in an X-ray mapping experiment? This broad question does not have a general answer, but here I present a simplified model of oxide nanoclusters (NCs) embedded in a metallic matrix. This model allows an *a priori* prediction of what features will be visible under given experimental conditions (specimen structure, microscope X-ray collection efficiency, beam current and pixel dwell time, etc.). The ability to estimate what combination of X-ray collection efficiency (as solid angle Ω), probe current (i_b), and pixel dwell time (τ), is necessary for given features to become visible in an X-ray map.

First, NCs in the matrix are simulated (Fig. 1a) and their relative densities of Fe and Ti projected down the beam direction (Z-axis)(Figure 1b-c). Application of the fundamental X-ray detection equation [1] and parameters [2,3] allows calculation of the anticipated Fe and Ti X-ray maps (Fig. 2a-b), which can incorporate finite spot size and beam broadening [4]; no bremsstrahlung contribution is (yet) present in the calculation. DTSA-II [5] is used to calculate ideal $Fe_{85}Cr_{14}W_1$ and $Y_2Ti_2O_7$ spectra. By scaling the spectra relative to the specific Ti and Fe counts calculated from the X-ray detection equation, each individual pixel's spectrum can be calculated (Fig. 3). Because the time-consuming Monte Carlo X-ray simulation is only performed twice (for the idealized matrix and NC spectra), it is very computationally efficient to populate the entire spectra; Fig. 3d). By generating full spectrum images (SIs), multivariate statistical analysis (MVSA) methods can be applied for datamining [6].

Comparisons to X-ray spectrum images taken on a Philips CM200, Hitachi HF3300, and FEI Titan G2 with ChemiSTEM are favorable when the input parameters to the model are well-matched to the experimental case. Fig. 5 compares Titan G2 data from simulation and experiment; the 4-detector SuperX system is well-suited to mapping small NCs embedded in a metallic matrix. Varying parameters such as SI size, probe current, pixel pitch, and pixel dwell time, all modify the visibility of the particles in a map, and are amenable to rapid screening by these calculations [7, 8].

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Fig. 2: Anticipated noisefree characteristic X-rays for (a) Fe (b) Ti.

Fig. 3: (a) Details of simulated count maps. (b) Idealized DTSA-II calculated spectra for matrix and precipitates. (c) Summed noise-free point spectrum. (d) With Poisson noise added.



Fig. 4: Top row experiment (NCSU Titan G2 with ChemiSTEM) and bottom row simulation, showing similar signals and visibilities. MVSA comp#2 denotes MVSA score image for precipiates. Inset value (i.e., 256×256) is binned pixel size for MVSA of original 512×512 map.